

<b>Notice of References Cited</b>	Application/Control No. 10/685,380	Applicant(s)/Patent Under Reexamination MAEKAWA, SHINJI	
	Examiner David Goodwin	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,612,251	03-1997	Lee, Jae-won	438/795
*	B	US-6,927,109	08-2005	Tanaka et al.	438/166
*	C	US-6,423,585	07-2002	Yamazaki et al.	438/166
*	D	US-2006/0019474	01-2006	Inui et al.	438/487
*	E	US-6,645,454	11-2003	Voutsas, Apostolos	423/348
*	F	US-2002/0151115	10-2002	Nakajima et al.	438/149
*	G	US-6,451,631	09-2002	Grigoropoulos et al.	438/149
*	H	US-2003/0003636	01-2003	Grigoropoulos et al.	438/149
*	I	US-6,884,699	04-2005	Ogawa et al.	438/489
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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